

Qualification Data for LFCSP Devices at ASE Korea

QUALIFICATION RESULTS 48-LFCSP			
TEST	CONDITIONS	SAMPLE SIZE (LOT/QTY)	RESULTS
High Temperature Storage (HTS)	JESD22-A103, 150°C, 1000 hours	1 x 45	Pass
Temperature Cycle*	JESD22-A104, -65°C to +150°C, 2 cycle per hour, 500 cycles	3 x 77	Pass
Biased HAST *	JESD22-A110, 130°C, 85% RH, 96hrs	3 x 77	Pass
Autoclave*	JESD22-A102, 121°C, 100% RH, 96hrs	3 x 77	Pass
Solder Heat Resistance (SHR)*	ADI-0049	3 x 15	Pass
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101, >500V	1 x 3	Pass

QUALIFICATION RESULTS 20-LFCSP			
TEST	CONDITIONS	SAMPLE SIZE (LOT/QTY)	RESULTS
High Temperature Storage (HTS)	JESD22-A103, 150°C, 1000 hours	1 x 40	Pass
Temperature Cycle*	JESD22-A104, -65°C to +150°C, 2 cycle per hour, 500 cycles	3 x 77	Pass
Biased HAST *	JESD22-A110, 130°C, 85% RH, 96hrs	3 x 77	Pass
Autoclave*	JESD22-A102, 121°C, 100% RH, 96hrs	3 x 77	Pass
Solder Heat Resistance (SHR)*	ADI-0049	3 x 15	Pass
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101, >1500V	1 x 3	Pass

*Preconditioned per JEDEC/IPC J-STD-020 MSL 3